L Number	Hits	Search Text	DB	Time stamp
1	3759		USPAT;	2004/10/18 09:51
		438/672.ccls. 438/675.ccls. 257/775.ccls.	US-PGPUB	
^2	3	6740916.pn. 6617631.pn. 6083788.pn.	USPAT;	2004/10/18 09:54
			US-PGPUB	
3	58	(438/595.ccls. 438/638.ccls. 438/639.ccls. 438/640.ccls.	USPAT;	2004/10/18 10:25
		438/672.ccls. 438/675.ccls. 257/775.ccls.) and ((gate wordline	US-PGPUB	
		bitline ((word bit metal coduct\$6) adj (line trace runner		
		interconnect\$6))) same (hole opening via trench groove		V.
		window) same (contact plug stud land\$6 pad) same (taper\$6		
		funnel conical cone))		
4	559	((gate wordline bitline ((word bit metal coduct\$6) adj (line	USPAT;	2004/10/18 10:29
		trace runner interconnect\$6))) same (hole opening via trench	US-PGPUB	
		groove window) same (contact plug stud land\$6 pad) same		,
		(taper\$6 funnel conical cone)) and (semiconductor wafer		
		silicon substrate)		
9	361	((hole opening via trench groove window) with (liner spacer	EPO; JPO;	2004/10/18 10:22
		sidewall (side adj wall))) and (contact plug stud land\$6 pad)	DERWENT;	
		and (taper\$6 funnel conical cone (isotropic\$8 with etch\$6)) and	IBM_TDB	
		(semiconductor wafer silicon substrate)		
12	784	(((hole opening via trench groove window) with (liner spacer	USPAT;	2004/10/18 10:28
		sidewall (side adj wall))) same (contact plug stud land\$6 pad)	US-PGPUB	
		same (taper\$6 funnel conical cone)) and (semiconductor wafer		
		silicon substrate)		
10	118	(438/595.ccls. 438/638.ccls. 438/639.ccls. 438/640.ccls.	USPAT;	2004/10/18 10:30
		438/672.ccls. 438/675.ccls. 257/775.ccls.) and ((gate wordline	US-PGPUB	
		bitline ((word bit metal coduct\$6) adj (line trace runner		
		interconnect\$6))) same (hole opening via trench groove		
		window) same (contact plug stud land\$6 pad) same (taper\$6		
		funnel conical cone (isotropic\$8 with etch\$6)))		
11	87	(438/595.ccls. 438/638.ccls. 438/639.ccls. 438/640.ccls.	USPAT;	2004/10/18 11:06
		438/672.ccls. 438/675.ccls. 257/775.ccls.) and (((hole opening	US-PGPUB	
		via trench groove window) with (liner spacer sidewall (side adj		
		wall))) same (contact plug stud land\$6 pad) same (taper\$6		
		funnel conical cone))		
13	111		USPAT;	2004/10/18 11:40
		trace runner interconnect\$6))) same ((hole opening via trench	US-PGPUB	
		groove window) with (liner spacer sidewall (side adj wall)))		
		same (contact plug stud land\$6 pad) same (taper\$6 funnel		
_		conical cone)) and (semiconductor wafer silicon substrate)		
7	204	(gate wordline bitline ((word bit metal coduct\$6) adj (line trace	EPO; JPO;	2004/10/18 12:07
		runner interconnect\$6))) and (hole opening via trench groove	DERWENT;	
		window) and (contact plug stud land\$6 pad) and (taper\$6	IBM_TDB	
		funnel conical cone) and (semiconductor wafer silicon		
		substrate)		200444044045
8	209		EPO; JPO;	2004/10/18 12:50
		sidewall (side adj wall))) and (contact plug stud land\$6 pad)	DERWENT;	
		and (taper\$6 funnel conical cone) and (semiconductor wafer	IBM_TDB	
_		silicon substrate)	116547	2004/40/40 44 45
5	317	1 113	USPAT;	2004/10/18 14:12
		trace runner interconnect\$6))) same ((hole opening via trench	US-PGPUB	
		groove window) with (taper\$6 funnel conical cone)) same		
		(contact plug stud land\$6 pad)) and (semiconductor wafer		
		silicon substrate)	<u></u>	